Page 1 of 1

AA 5,909,318 6/1/99 Tanaka 359 689 AB 6,545,819 4/8/03 Nanba et al. 359 689 AC 2003/0072085 4/17/03 Mizuguchi et al. 359 680 AD 6,349,002 2/19/02 Shibayama et al. 359 689 AE AF FOREIGN PATENT DOCUMENTS Examiner Document Number Date Country Class Sub- Translation	- '		FORM PTO-	1449		Atty. Docket	No.	Appli	n. No.
Applicant Keiko MIZUGUCHI et al. Filing Date HEREWITH U.S. PATENT DOCUMENTS Examiner Initial AA 5,909,318 6/1/99 Tanaka 359 689 AB 6,545,819 4/8/03 Nanba et al. 359 689 AC 2003/0072085 4/17/03 Mizuguchi et al. 359 689 AD 6,349,002 2/19/02 Shibayama et al. 359 689 AE AF AG AH AH AI FOREIGN PATENT DOCUMENTS Examiner Initial POCUMENT Number Date Country Class Sub- Class Translation Translation AJ AK AL AM AN AN AN AN AN AO OTHER (including author, title, date, pertinent pages, etc.)						XA-9926			
Reiko MIZUGUCHI et al. Filing Date Group	LIST	OF	DOCUMENTS CIT	ED BY APP	LICANT				
Filing Date HEREWITH					Applicant				
HEREWITH			,				UGUCHI	et al.	
Document Number Date Name Class Sub-class Filing Date Class Sub-class Namba et al. 359 689								Group	P
Document Number Date Name Class Sub-class Filing Date Name Class Sub-class Filing Date Name Class Sub-class Filing Date Name Name Class Sub-class Sub-class Sub-class Name						HEREWITH			
AA				U.S. P.	ATENT DO	CUMENTS		•	
AB 6,545,819 4/8/03 Nanba et al. 359 689 AC 2003/0072085 4/17/03 Mizuguchi et al. 359 680 AD 6,349,002 2/19/02 Shibayama et al. 359 689 AE AF AG AH AI FOREIGN PATENT DOCUMENTS Examiner Initial AJ AK AL AM AN AN AN AN AN AN AN AN AN			Document Number	Date		Name	Class		Filing Date
AC 2003/0072085 4/17/03 Mizuguchi et al. 359 680 AD 6,349,002 2/19/02 Shibayama et al. 359 689 AE AF AF AG AG AH AH AI BAT AI BAT AN AN AN AO OTHER (including author, title, date, pertinent pages, etc.)	918	AA	5,909,318	6/1/99	Tanaka	359		689	
AC 2003/0072085 4/17/03 Mizuguchi et al. 359 680 AD 6,349,002 2/19/02 Shibayama et al. 359 689 AE AF AF AG AG AH AH AI BAT AI BAT AN AN AN AO OTHER (including author, title, date, pertinent pages, etc.)	9/8	AB	6,545,819	4/8/03	Nanba e	t al.	359	689	
AE AF AG AH AI FOREIGN PATENT DOCUMENTS Examiner Initial Document Number Date Country Class Subclass Translation Class AJ AK AL AN AN AN AN AN AN AN AN AN		AC	2003/0072085	4/17/03	Mizuguc	hi et al.	359	680	
AF AG AH AI FOREIGN PATENT DOCUMENTS Examiner Initial AJ AV AK AL AL AM AN AN AN AN AN AO OTHER (including author, title, date, pertinent pages, etc.)	4/1	AD	6,349,002	2/19/02	Shibaya	ma et al.	359	689	
AG AH AI FOREIGN PATENT DOCUMENTS Examiner Initial AJ AK AL AR AM AN AN AO OTHER (including author, title, date, pertinent pages, etc.)	,	AE		-					
AH AI FOREIGN PATENT DOCUMENTS Examiner Initial Document Number Date Country Class Subclass Translation Class AJ AK AL AM AN AN AN AN AO OTHER (including author, title, date, pertinent pages, etc.)		AF							
FOREIGN PATENT DOCUMENTS Examiner Initial Document Number Date Country Class Subclass Translation AJ AK AL AM AN AN AN AN AN AN AN AO OTHER (including author, title, date, pertinent pages, etc.)		AG							
FOREIGN PATENT DOCUMENTS Examiner Initial Document Number Date Country Class Subclass Translation Class AJ		АН						,	
AX AL AM AN		AI			-	<u> </u>			
AJ AK AL AM AN AN AO Class Class Class Chass Class Chass Ch		-		FOREIGN	PATENT I	OCUMENTS	! <u></u>	<u> </u>	
AK AL AM AN AN AO OTHER (including author, title, date, pertinent pages, etc.)	Examiner Initial		Document Number	Date		Country			Translation
AL AM AN AO OTHER (including author, title, date, pertinent pages, etc.)		АJ							· · · · · · · · · · · · · · · · · · ·
AM AN AO OTHER (including author, title, date, pertinent pages, etc.)	_	AK							
AN AO OTHER (including author, title, date, pertinent pages, etc.)		AL							
OTHER (including author, title, date, pertinent pages, etc.)		AM							
OTHER (including author, title, date, pertinent pages, etc.)		AN							
		AO				***			
AP			OTHER (in	cluding author	r, title, dat	te, pertinent p	ages, etc.	.)	
	,	AP	-						·
AQ		AQ							
AR		AR	- A1				····	 -	
Date Considered	Examine		TSugar		Date				
S.J. Sygarman Date Considered 12-2004	YAMTAIR	<u> </u>	J.J. Jam	on		•	-		
XAMINER: Initial if reference considered, whether or not citation is in conformance ith MPEP 609; draw line through citation if not in conformance and not considered not copy of this form with next communication to Applicant.	ith MP	EP 6	09; draw line th	rough cita	tion if n	ot in confo	rmance a	n is in and not	conformance considered.

Page 1 of 1

		FORM PTO-1	.449	Atty. Docket No. Appln. No.						
				XA-9926		10/6	10/651,201			
LIST	OF	DOCUMENTS CITE	ED BY APP							
		OF			Applicant					
		61,5			Keiko MIZUGUCHI et al.					
	_ {	HON O 4 YOUR ST	_		Filing Date	Filing Date Group				
	1	\·			August 29, 2003 2872					
U.S. PATENT DOCUMENTS										
Examiner Initial	iner Document Number Date				Name	Class	Sub- class	Filing Date		
56/1	AA	2003/0123156	7/3/03	Minefuj	ji	359	682			
	AB			1						
	AC			 						
	AD			1						
	AE									
	AF			 				 		
ļ	AG			†						
	AH			+						
	AI	+	<u> </u>							
FOREIGN PATENT DOCUMENTS										
Examiner Initial		Document Number	Date		Country	Class	Sub- class	Translation		
A	AJ	2003-107351	4/9/03	Japa	n		_	Yes		
Cho	AK	2003-57545	2/26/03	Japan			-	Yes		
	AL									
	AM									
	AN									
	AO									
OTHER (including author, title, date, pertinent pages, etc.)										
	AP									
	AQ									
	AR									
Examiner S.J. Sygaman Date Considered 12-2004										
EXAMINE	₹:	Initial If refer	ence consi	dered, wh	ether or not	citatio	n is in	conformance		
with MP.	EP 6	509; draw line they of this form wi	hrough cita	ation if	not in confo	rmance a	and not	considered.		